Japan FPD Materials & Components Committee and Japan FPD Metrology Committee Joint Meeting
Meeting Summary and Minutes

SEMI Japan Standards Spring 2013 Meetings
April 12, 2013, 15:00-17:00
Room 508, Campus Innovation Center (Yamagata University Tokyo Satellite)
Tokyo, Japan

Next Committee Meeting
FPD M&C Committee:
SEMI Japan Standards Summer 2013 Meetings
Friday, July 5, 2013, 15:00-17:00
SEMI Japan, Tokyo, Japan

FPD Metrology Committee:
SEMI Japan Standards Fall 2013 Meetings
TBD (Candidate is sometime in October or November)

Table 1 Meeting Attendees

Co-Chairs of FPD M&C Committee: Hisashi Aruga (Seiko Epson), Tadahiro Furukawa (Yamagata University), Yoshi Shibahara (Fujifilm)

Co-Chairs of FPD Metrology Committee: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)

SEMI Staff: Naoko Tejima (SEMI Japan)

Company	*Last*	*First*	*Company*	*Last*	*First*
Yamagata University	Furukawa	Tadahiro	Konica Minolta	Ochi	Keizo
Teijin	Itoh	Haruhiko	Fujifilm	Shibahara	Yoshi
Otsuka Electronics	Kawaguchi	Akira	Japan Display	Watanabe	Ryoichi
Sumitomo Chemical	Kuroda	Toshiya	SEMI Japan	Tejima	Naoko
SK Electronics	Nogami	Yoshitada			

** alphabetical order by last name*

Table 2 Leadership Changes

None

Table 3 Ballot Results

None

Table 4 Authorized Ballots

None

Table 5 Authorized Activities

None

Table 6 New Action Items

Item #	*Assigned to*	*Details*
FPD M&C121102-02	SEMI Staff	To ask, through SEMI Korea Staff, members of FPD Committee in Korea what they want to do with respect to D41; - should be maintained or - can be “Inactive” document
FPD M&C130208-02	SEMI Staff	To submit reapproval ballot of SEMI D13 for Cycle 3, 2013
FPD M&C130208-03	SEMI Staff	To submit reapproval ballot of SEMI D29 for Cycle 3, 2013
FPD M&C130208-04	SEMI Staff	To submit reapproval ballot of SEMI D30 for Cycle 3, 2013
FPD M&C130412-01	SEMI Staff	To correct the Committee Co-chairs’ names of Table 1 of the previous meeting
FPD M&C130412-02	SEMI Staff	To send the document template to Flexible Display TF leaders.
FPD M&C130412-03	SEMI Staff	To check the background and reasons why “Measure Method" should be changed to “Test Method" (Subtypes of Standards of Doc.#5555).
FPD M&C130412-04	SEMI Staff	To ask the TF leaders to translate D46 into Japanese, providing the difference file.
FPD MET 130412-01	SEMI Staff	To ask the TF leaders to translate D31 into Japanese, providing the difference file.
FPD Coord.130412-01	JRSC co-chairs/ SEMI staff	To discuss the best way to restructure JA FPD committees, and based on the result, discuss it with JA FPD Coordination group.
FPD Coord.130412-02	SEMI Staff	To set the meeting between JRSC Co-chairs, JA FPD Co-chairs and SEMI Staff
FPD Coord.130412-03	SEMI Staff	To check whether NA FPD committee exist or not.

[Common Part 1]

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa, committee co-chair, called the meeting to order at 15:00. Self-introductions were made followed by the agenda review.

2 Required Meeting Elements

The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed by SEMI staff, Naoko Tejima.

3 SEMI Staff Report

Naoko Tejima gave the SEMI staff report. This report included SEMI Global 2013 Calendar of Events, NA Standards Spring 2013 Meetings, 2013 Critical Dates for SEMI Standards Ballots, SEMI Standards Publication, ISC Audits & Reviews SC Summary, New Standards Ballot and Membership Systems, New Ballot Formatting Templates, Style Manual and Compilation of Terms, Revised SEMI Regulations & Procedure Guide and Contact Information.

Attachment: 01_SEMI_Staff_Report_130412

4 Liaison Reports

4.1 *Korea FPD Committee Report*

Naoko Tejima reported for the Korea FPD Metrology Committee. This report included Leadership, Organization Chart, Meeting Information, Ballot Results, Upcoming Ballots, Subcommittee/TF/WG Reports, Contact Information.

Attachment: 02_KR_FPD_Liaison_Report_130412

4.2 *Taiwan FPD Committee Report*

Naoko Tejima reported for the Taiwan FPD Committee. This report included Leadership, Organization Chart, Meeting Information, New Task Force, New SNARFs, Upcoming Ballots in 2013, FPD Committee Highlights, Contact Information.

Attachment: 03_TW_FPD_Liaison Report_130412

[Japan FPD Materials & Components Committee Part]

5 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting held on February 8, 2013.

It was pointed that the Committee Co-chairs' names of Table 1 are wrong and should be corrected.

Motion: To approve the minutes of the previous meeting as written after the above point is corrected.

By / 2nd: Ryoichi Watanabe (Japan Display) / Yoshi Shibahara (Fujifilm)

Discussion: None

Vote: 7 in favor and 0 opposed. **Motion passed.**

Action Item: SEMI staff to correct the Committee Co-chairs' names of Table 1 of the previous meeting minutes.

Attachment: 04_JA_FPD_M&C_Previous_Mtg_Minutes_130412

6 Task Force Reports

6.1 *Polarizing Film Task Force*

Yoshi Shibahara reported on progress for the Polarizing Film Task Force. The Task Force met earlier in the day. Of note:

- *SEMI D46-0213, Terminology for FPD Polarizing Films* was published
- TF will start to work for *Doc. #5555, Revision to SEMI D50-0707, Test Method for Surface Hardness of FPD Polarizing Film,* from the next TF meeting.
- TF discussed whether there are the new standards should be developed. If it is confined to the Polarizing Film, there can not be found any special topics. TF continuously discusses it with more wide scope such as touch screen panels and optical measuring at the next meeting

Attachment: 05_Polarizer_TF_Report_130412

6.2 *Backlight Task Force*

No report was provided by the Task Force.

6.3 *Flexible Display Task Force*

6.3.1 Doc. #5550, New Standard: Guide for Dimensional Measurement of Plastic Films

Haruhiko Itoh reported on progress for the development of the above document. Of note:

- TF examined the result of questionnaire about the Measurement Condition for Plastic Substrate/Film Dimension and Curl/Bending.
- This Document is a guideline and it should not be included the specific measurement method and measurement environment. On the other hand, it should be identified how the plastic substrates change.
- TF will start to draft the standard document from the next meeting.

Action Item: SEMI Staff to send the document template to Flexible Display TF leaders.

Attachment: 06_Questionnaire_Plastic_Substrate_130412

6.3.2 Doc. #5551, Measurement Method of Water Vapor Transmission Rate for Plastic Films and Sheets with High Barrier Properties for Electronic Devices

Tadahiro Furukawa reported on progress for the development of the above document. Of note:

- TF has not discussed specifically yet.
- SEMI staff requested to TF to change the title of “Measurement Method” to "Test Method", one of the defined Subtypes of Standards (Classification, Guide, Practices, Specifications, Terminology, Test Method) on the Regulations.
- TF’s opinion to this request is as follows; Since "Measurement Method" has different meaning from "Test Method", it has been used so far. However, if it is needed to change, they need to know the background of this request for the judgment.

Action Item: SEMI staff to check the background and reasons why “Measure Method" should be changed to “Test Method".

6.4 *Color Filter Task Force*

Tadahiro Furukawa reported for the Color Filter Task Force that there were no particular things should be reported.

6.5 *5-year-Review*

Naoko Tejima reported for the present status of documents for 5-year-review procedure. Of note:

- Will be submitted for Cycle 3, 2013
  - ✓ SEMI D13-0708
  - ✓ SEMI D29-1101 (Reapproved 0707)
  - ✓ SEMI D30-0707
- Working to revise in the Korea FPD Committee
  - ✓ SEMI D33-0703 (Doc.4859A)
  - ✓ SEMI D36-0306 (Doc.5379C)
- Working to revise in the Polarizing Film Task Force (JA FPDM&C Committee)
  - ✓ SEMI D50-0707 (Doc.5555)
- Checking Korea Committee’s intention
  - ✓ SEMI D41-0305

- Inactive
    - ✓ SEMI D24-0200 (Reapproved 0706)
    - ✓ SEMI D25-0600E (Reapproved 0706)
    - ✓ SEMI D47-0307

Attachment: 07_5-year-Review for FPD_130412

7 Old Business

7.1 *Previous Meeting Action Items*

Naoko Tejima reviewed the previous meeting action items.

Table 7 Previous Meeting Actions Items

Item #	*Assigned to*	*Details*
FPD M&C121102-01	Chairs	To work on the documents of substrate and backlight for five-year review … **Close**
FPD M&C121102-02	SEMI Staff	To ask, through SEMI Korea Staff, members of FPD Committee in Korea what they want to do with respect to D41; - should be maintained or - can be "Inactive" document … **Open**
FPD M&C 130208-01	SEMI Staff	To create an opportunity to explain about the Revised SEMI Regulations & Procedure Guide … **Close**
FPD M&C 130208-02	SEMI Staff	To submit reapproval ballot of SEMI D13 for Cycle 3, 2013 … **Open**
FPD M&C 130208-03	SEMI Staff	To submit reapproval ballot of SEMI D29 for Cycle 3, 2013 … **Open**
FPD M&C 130208-04	SEMI Staff	To submit reapproval ballot of SEMI D30 for Cycle 3, 2013 … **Open**

8 New Business

None

[Japan FPD Metrology Committee Part]

9 SEMI Technical Award

Technical Committee Awards were given to the below member to appreciate his outstanding efforts and leadership.

- Keizo Ochi (Konica Minolta) – D31 Revision Task Force activities

10 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting held on November 2, 2012.

Motion: To approve the minutes of the previous meeting as written.

By / 2nd: Akira Kawaguchi (Otsuka Electronics) / Keizo Ochi (Konica Minolta)

Discussion: None

Vote: 7 in favor and 0 opposed. **Motion passed.**

Attachment: 08_JA_FPD_Metrology_Previous_Mtg_Minutes_130412

11 Task Force Reports

11.1 *D31 Revision Task Force*

Keizo Ochi reported on progress for the *D31 Revision* Task Force. Of note:

- *SEMI D31-0213, Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection* was published
- The TF will be disbanded after the document was translated in Japanese.

Action Item: SEMI staff to ask the TF leaders to translate D31 into Japanese, providing the difference file.

Action Item: SEMI staff to ask the TF leaders to translate D46 into Japanese, providing the difference file.

12 Old Business

12.1 *Previous Meeting Action Items*

Naoko Tejima reviewed the previous meeting action items.

Table 8 Previous Meeting Actions Items

Item #	*Assigned to*	*Details*
FPD MET 121102-01	Chairs/ SEMI Staff	To report leadership change to JRSC … **Close**

13 New Business

None

[FPD Coordination Group Part]

14 Future Plan of FPD Committees

Tadahiro Furukawa explained the background and the present status of Japan FPD Committees so far. Of note:

- According to the result of the discussion at the ad-hoc Japan FPD Materials & Components Committee, Japan FPD Mask Committee and Japan FPD Factory Automation Committee Ad-hoc Joint Meeting, the followings were proposed to JRSC (December 3).
  - ✓ To merge the following three committees and to make a Japan FPD Committee
    - Japan FPD Materials & Components Committee (Keep this committee)
    - Japan FPD Mask Committee (Be merged to “FPD Committee)
    - Japan FPD FA Committee (Be merged to “FPD Committee)
  - ✓ To keep the Japan FPD Metrology Committee as is
- The above proposal passed JRSC review, however, it did not passed ISC review and was returned to re-discuss to the Japan FPD Committees, since it should be considered the global organization which is mutually compatible between each locale, not only Japan.
- On December, 2012, the regulation was revised. According to the new regulation, in order to restructure the global organization of the FPD committee, some problems must be solved.

Ryoichi Watanabe explained the part of the revised regulations related to the organization restructure.

Global FPD TC (Current)

Global	Japan	Taiwan	Korea	NA
M&C	M&C	FPD	FPD	FPD (should be checked)
Mask	Mask			
FA	FA			
Metrology	Metrology		Metrology	

Global FPD TC (According to the new regulation)

Global	Japan	Taiwan	Korea	NA
M&C	M&C			
Mask	Mask	FPD	FPD	FPD
FA	FA			(should be checked)
Metrology	Metrology		Metrology	

Action Item: JRSC co-chairs and SEMI staff to discuss the best way to restructure JA FPD committees, and based on the result, discuss it with JA FPD Coordination group.

Action Item: SEMI staff to set the meeting between JRSC Co-chairs, JA FPD Co-chairs and SEMI Staff

Action Item: SEMI staff to check whether NA FPD committee exist or not.

Attachment: 09_JA_FPD_Ad-hoc_Previous_Mtg_Minutes_130412

[Common Part 2]

15 Action Item Review

15.1 *New Action Items*

Naoko Tejima reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

16 Next Meeting and Adjournment

The next meeting of the Japan FPD Materials & Components Committee is scheduled for Friday, July 5, 2013, 15:00-17:00, SEMI Japan, Tokyo, Japan

The next meeting of the Japan FPD Metrology Committee is TBD (Candidate is sometime in October or November). It will be held jointly with the Japan FPD Materials & Components Committee.

Respectfully submitted by:
Naoko Tejima
Manager, Standards
SEMI Japan
Phone: +81.3.3222.5804
Email: ntejima@semi.org

Minutes approved by:

Tadahiro Furukawa (Yamagata University), Co-chair of JA FPD M&C Committee	May 16, 2013
Yoshi Shibahara (Fujifilim), Co-chair of JA FPD M&C Committee	May 15, 2013
Ryoichi Watanabe (Japan Display), Co-chair of JA FPD Metrology Committee	May 15, 2013
Akira Kawaguchi (Otsuka Electronics) , Co-chair of JA FPD Metrology Committee	

Table 9 Index of Available Attachments [#1]

#	*Title*
1	SEMI_Staff_Report_130412
2	KR_FPD_Liaison_Report_130412
3	TW_FPD_Liaison_Report_130412
4	JA_FPD_M&C_Previous _Mtg_Minutes_130412
5	Polarizer_TF_Report_130412
6	Questionnaire_Plastic_Substrate_130412
7	5-year-Review_for_FPD_130412
8	JA_FPD_Metrology_Previous_Mtg_Minutes_130412
9	JA_FPD_Ad-hoc_Previous_Mtg_Minutes_130412

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Naoko Tejima at the contact information above.